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Front Matter: Volume 8661

, "Front Matter: Volume 8661," Proc. SPIE 8661, Image Processing: Machine Vision Applications VI, 866101 (26 March 2013); doi: 10.1117/12.2025008

SPIE.

Event: IS&T/SPIE Electronic Imaging, 2013, Burlingame, California, United States

Image Processing: Machine Vision Applications VI

**Philip R. Bingham
Edmund Y. Lam**
Editors

**5–6 February 2013
Burlingame, California, United States**

Sponsored by
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Published by
SPIE

Volume 8661

Proceedings of SPIE 0277-786X, V.8661

Image Processing: Machine Vision Applications VI, edited by Philip R. Bingham, Edmund Y. Lam,
Proc. of SPIE-IS&T Electronic Imaging, SPIE Vol. 8661, 866101 · © 2013 SPIE-IS&T
CCC code: 0277-786X/13/\$18 · doi: 10.1117/12.2025008

SPIE-IS&T/ Vol. 8661 866101-1

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Author(s), "Title of Paper," in *Image Processing: Machine Vision Applications VI*, edited by Philip R. Bingham, Edmund Y. Lam, Proceedings of SPIE-IS&T Electronic Imaging, SPIE Vol. 8661. Article CID Number (2013)

ISSN: 0277-786X

ISBN: 9780819494344

Copublished by

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P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time)· Fax +1 360 647 1445

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IS&T—The Society for Imaging Science and Technology

7003 Kilworth Lane, Springfield, Virginia, 22151 USA

Telephone +1 703 642 9090 (Eastern Time)· Fax +1 703 642 9094

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Printed in the United States of America.

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